

PLUS Search Results for S/N 10689553, Searched March 24, 2005

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5426651
5703885
5796752
6004027
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5630051
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10689553_QUAL.txt

5426651 81
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5659555 81
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5228040 67
5623499 67
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5239270 49
5574733 48
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5333197 48
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10689553_WEST.txt

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5673275 4601032 4939396 5668481 5768289 6069829 4261041 4455654 4465995 4477870).pn.

10689553_CLS.txt

Most Frequently Occurring Classifications of Patents Returned
From A Search of 10689553 on March 24, 2005

original classifications

7 714/738
4 714/724
2 702/183
2 716/4

Cross-Reference Classifications

4 714/718
3 714/734
3 714/736
3 716/4
2 257/E21.525
2 702/185
2 714/704
2 714/723
2 714/733
2 714/738
2 716/2
2 716/5
2 716/6

Combined Classifications

9 714/738
5 714/724
5 716/4
4 714/718
3 714/734
3 714/736
2 257/E21.525
2 365/201
2 438/14
2 702/183
2 702/185
2 714/33
2 714/704
2 714/723
2 714/727
2 714/733
2 716/2
2 716/5
2 716/6

10689553_CLSTITLES.txt

Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10689553 on March 24, 2005

9 714/738 (7 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/738 ..Including test pattern generator

5 714/724 (4 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing

5 716/4 (2 OR, 3 XR)
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK
716/1 CIRCUIT DESIGN
716/4 .Testing or evaluating

4 714/718 (0 OR, 4 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/718 .Memory testing

3 714/734 (0 OR, 3 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/734 ..Structural (in-circuit test)

3 714/736 (0 OR, 3 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/736 ..Device response compared to expected
fault-free response

2 257/E21.525 (0 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/E21.515Involving use of mechanical auxiliary part
without use of alloying or soldering process, e.g.,
pressure contacts (EPO)
257/E21.521 .Testing or measuring during manufacture or
treatment or reliability measurement, i.e., testing of
parts followed by no processing which modifies parts as
such (EPO)
257/E21.525 ..Procedures, i.e., sequence of activities
consisting of plurality of measurement and correction,
marking or sorting steps (EPO)

2 365/201 (1 OR, 1 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/201 .Testing

2 438/14 (1 OR, 1 XR)

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Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
438/14 WITH MEASURING OR TESTING

2 702/183 (2 OR, 0 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/127 MEASUREMENT SYSTEM
702/182 .Performance or efficiency evaluation
702/183 ..Diagnostic analysis

2 702/185 (0 OR, 2 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/127 MEASUREMENT SYSTEM
702/182 .Performance or efficiency evaluation
702/183 ..Diagnostic analysis
702/185 ...Cause or fault identification

2 714/33 (1 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
714/1 .Reliability and availability
714/25 ..Fault locating (i.e., diagnosis or testing)
714/32 ...Particular stimulus creation
714/33Derived from analysis (e.g., of a
specification or by stimulation)

2 714/704 (0 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/704 .Error count or rate

2 714/723 (0 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/718 .Memory testing
714/723 ..Error mapping or logging

2 714/727 (1 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
design (LSSD))
714/727 ...Boundary scan

2 714/733 (0 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/733 ..Built-in testing circuit (BILBO)

2 716/2 (0 OR, 2 XR)
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK

10689553_CLSTITLES.txt
716/1 CIRCUIT DESIGN
716/2 .Optimization (e.g., redundancy, compaction)

2 716/5 (0 OR, 2 XR)
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK
716/1 CIRCUIT DESIGN
716/4 .Testing or evaluating
716/5 ..Design verification (e.g., wiring line
capacitance, fan-out checking, minimum path width)

2 716/6 (0 OR, 2 XR)
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK
716/1 CIRCUIT DESIGN
716/4 .Testing or evaluating
716/5 ..Design verification (e.g., wiring line
capacitance, fan-out checking, minimum path width)
716/6 ...Timing analysis (e.g., delay time, path
delay, latch timing)

10689553_EAST.txt

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5937188
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10689553_WDS.txt

above 2
abstmct 1
academically 1
according 2
action 2
addition 2
algorithm 3
algorithms 2
all 3
almost 1
also 3
am 2
an 4
and 43
another 3
appamitus 1
apparatus 5
application 1
applied 1
applies 1
apply 2
applying 2
are 6
art 1
as 6
assignment 1
attached 1
automation 1
based 4
be 9
behavior 1
belief 1
best 1
brief 1
but 1
by 19
cal 1
called 2
can 8
case 2
cause 1
certification 1
certify 1
check 13
checked 3
chome 1
combinatorial 1
common 2
communication 14
complete 3
composition 2
concatenate 2
concatenating 2
conformance 1
conjunctive 4
consider 1
considering 5
constraints 2
construct 1
construction 1
constructs 1
contained 1
conventional 3

10689553_WDS.txt

conversant 1
convert 1
converting 6
converts 3
correct 1
correctly 5
correctness 2
corresponding 2
data 1
date 1
declare 1
depends 1
derived 1
described 5
describing 2
description 3
design 1
detmled 1
dhcp 1
diagram 22
diaram 1
disclosure 1
distinguish 1
do 1
document 1
does 1
drawings 1
ds 2
each 6
eakawa 1
either 1
electronic 1
embodiment 9
english 2
execute 3
executed 1
executing 4
exist 1
existence 2
exists 5
field 1
fig 24
finite 3
first 3
flowchart 1
following 1
for 28
form 4
formqla 1
formula 5
from 3
fsm 34
fsms 1
furthermore 1
genemte 1
general 2
generate 19
generated 4
generates 7
generating 10
generation 16
get 1
given 11

10689553_WDS.txt

hand 1
has 1
have 6
here 2
however 2
identify 1
if 3
ilowchart 1
implementation 4
implemented 6
improved 1
in 25
ing 1
initial 2
input 11
inputting 3
into 1
invention 19
inwntion 1
is 44
it 1
its 2
jut 8
japanease 1
jts 1
knowledge 1
known 2
ku 1
languages 1
lead 1
length 8
lenlh 1
like 1
lo 1
longer 1
loops 1
lune 1
machine 3
machines 2
maximum 2
may 3
method 8
methods 2
minimum 5
modeled 1
modi 1
modified 6
modifying 2
more 1
moves 1
multiple 4
my 1
nao 2
needed 1
nippori 1
nishi 1
no 1
nor 1
normal 4
not 3
np 3
obtain 1
obtained 3

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oda 2
of 79
on 7
one 1
only 1
optimization 1
or 7
order 1
other 2
output 7
overlap 1
overlapping 7
page 8
particularly 1
parts 2
patent 1
performance 1
pertains 1
practical 2
preceding 7
prefered 1
present 17
problem 39
problems 2
process 1
proposed 1
proposes 3
protocol 10
protocols 12
quickly 1
recently 1
related 1
relates 2
represented 1
representing 8
represents 1
reset 2
result 6
return 1
sat 19
satisfiability 1
satisfiable 2
second 4
section 4
selection 1
self 1
sequences 1
sequence 56
sequences 44
serial 1
shorter 2
should 1
shows 23
since 2
single 1
so 2
solver 2
solves 1
solving 5
sometimes 1
specification 11
specilcation 1
state 36

10689553_WDS.txt

states 8
step 12
subsequence 3
subsequences 4
such 4
summary 1
technical 1
technique 1
test 66
tested 1
testing 1
that 5
the 217
then 2
there 5
these 2
time 2
title 1
to 56
tokyo lapu hereby 1
transition 10
transitions 7
translation 1
translator 2
true 1
truth 1
two 1
ui 3
ui o 19
uios 1
under 2
unique 1
use 2
using 2
value 1
variables 1
we 14
when 4
whether 11
whi 1
which 36
with 1
without 1
would 1
xq 1
xsxq 1